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In the Claims

1. (presently amended) A method for forming a ruthenium metal layer comprising the following steps:

providing a ruthenium precursor and oxygen in a chamber to form a ruthenium oxide layer; and

heating said ruthenium oxide layer in the presence of a hydrogen-rich gas to form a convert said ruthenium oxide layer to a smooth-surfaced ruthenium metal layer.

- 2. (original) The method of claim 1 further comprising the step of introducing oxygen into said chamber at a flow rate of between about 10 sccm to about 1000 sccm during said step of providing said precursor and said oxygen in said chamber.
- 3. (original) The method of claim 1 further comprising the step of introducing oxygen into said chamber at a flow rate of between about 150 sccm to about 250 sccm during said step of providing said precursor and said oxygen in said chamber.
- 4. (presently amended) A method for forming a ruthenium metal layer comprising the following steps:

providing a ruthenium precursor at a flow rate of between about 10 sccm and about 2000 sccm and oxygen at a flow rate of between about 10 sccm and about 1000 sccm in a chamber at a pressure of between about 0.1 Torr and about 90 Torr and at a temperature of between about 100°C and about 600°C to form a ruthenium oxide layer; and

heating said ruthenium oxide layer to a temperature of between about 400°C to about 800°C for between about 10 seconds and about five minutes at a pressure of between about 1 Torr and about 760 Torr in the presence of a hydrogen-rich gas at a flow rate of between about 100 sccm and about 10,000 sccm to convert said ruthenium oxide layer to a smooth-surfaced ruthenium metal layer.

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5. (presently amended) The method of claim 4 wherein said step of providing said ruthenium precursor comprises the step of providing a material selected from the group consisting of CHDR tricarbonyl-1,3-cyclohexadiene ruthenium, Ru(EtCp)₂ bisethylcyclopentadienylruthenium, and Ru(OD)₃ ruthenium octanedionate.

- 6. (presently amended) The method of claim 4 further comprising the step of providing a hydrogen-rich gas selected from the group consisting of ammonia and hydrogen gas during said heating of said ruthenium oxide layer step.
- 7. (presently amended) A method used to form a ruthenium metal layer comprising the following steps:

forming a ruthenium oxide layer in a chamber by providing a ruthenium precursor at a flow rate of between about 10 sccm and about 2000 sccm and oxygen at a flow rate of between about 10 sccm and about 1000 sccm at a temperature of between about 100°C and about 600°C and a pressure of between about 0.1 Torr to about 90 Torr; and

annealing said ruthenium oxide layer at a temperature of between about 400°C and about 800°C in the presence of a hydrogen-rich gas at a flow rate of between about 100 sccm and about 10,000 sccm and a chamber pressure of between about 1 Torr and about 760 Torr to convert said ruthenium oxide layer to a smooth-surfaced ruthenium metal layer.

8. (original) The method of claim 7 further comprising the following steps:

forming said ruthenium oxide layer in said chamber by providing said ruthenium precursor at a flow rate of between about 100 sccm and about 1000 sccm and said oxygen at a flow rate of between about 100 sccm and about 1000 sccm at a temperature of between about 150°C and about 450°C and a pressure of between about 1 Torr to about 9 Torr; and

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during said annealing step, heating said ruthenium oxide layer to a temperature of between about 450°C and about 750°C in the presence of a hydrogen-rich gas at a flow rate of between about 500 sccm and about 8,000 sccm at a pressure of between about 100 Torr to about 660 Torr.

9. (original) The method of claim 8 further comprising the following steps:

forming said ruthenium oxide layer in said chamber by providing said ruthenium precursor at a flow rate of about 500 sccm and said oxygen at a flow rate of about 200 sccm and a temperature of about 210°C; and

during said annealing step, heating said ruthenium oxide layer to a temperature of between about 475°C to about 650°C in the presence of a hydrogenrich gas at a flow rate of between about 3,000 sccm and about 6,000 sccm.

- 10. (original) The method of claim 9 further comprising the step of annealing said ruthenium oxide layer for a duration of between about 10 seconds and about five minutes during said annealing step.
- 11. (original) The method of claim 10 further comprising the step of annealing said ruthenium oxide layer for a duration of between about 30 seconds and about three minutes.
- 12. 20. (canceled)